

Application/Control No.	Applicant(s)/Patent under Reexamination
10/786,388	STRECK ET AL.
Examiner	Art Unit
Rinh Y Tran	1765

SEARCHED					
Class	Subclass	Date	Examiner		
438	746	3/14/2006	ВТ		
438	747	3/14/2006	вт		
438	756	3/14/2006	ВТ		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
	1				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Search keywords and inventor's names using USPAT, USPG-PUB, JPO, EPO, DERWENT databases	3/14/2006	ВТ		
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